

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination CLEVINGER ET AL.	
		Examiner Ginette Peralta	Art Unit 2814	Page 1 of 1

U.S. PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Toyoda, H. et al.; "Improvement in the Electromigration Lifetime Using Hyper-Textured Aluminum Formed on Amorphous Tantalum-Aluminum Underlayer"; 32 nd Annual Proceedings Reliability Physics Symposium, 11-14 April, 1994. IEEE International, pp. 178-184
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